



DMN2004VK

COMPLEMENTARY PAIR ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

Features

- Low On-Resistance
- Low Gate Threshold Voltage V_{GS(th)} <1V
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Complementary Pair MOSFET
- Ultra-Small Surface Mount Package
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- ESD Protected Gate
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

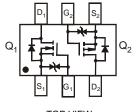
Mechanical Data

- Case: SOT-563
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020C
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe.
 Solderable per MIL-STD-202, Method 208 (23)
- Weight: 0.006 grams (approximate)









TOP VIEW

BOTTOM VIEW

TOP VIEW Internal Schematic

Ordering Information (Note 4)

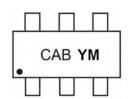
| Part Number | Case | Packaging |
|-------------|---------|------------------|
| DMC2004VK-7 | SOT-563 | 3000/Tape & Reel |

SOT-563

Notes:

- 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. All applicable RoHS exemptions applied.
- 2. See http://www.diodes.com for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/datasheets/ap02007.pdf.

Marking Information



CAB = Product Type Marking Code YM = Date Code Marking Y = Year ex: U = 2007 M = Month ex: 9 = September

Date Code Key

| Year | Year 2007 2008 | | 2009 2010 | | 2011 | | 2012 | | | | | |
|-------|----------------|-----|-----------|-----|------|-----|------|-----|-----|-----|-----|-----|
| Code | Code U V | | V | V | X | | Υ | | Z | | | |
| Month | Jan | Feb | Mar | Apr | May | Jun | Jul | Aug | Sep | Oct | Nov | Dec |
| Code | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 0 | N | D |



Maximum Ratings N-CHANNEL − Q₁ (@T_A = +25°C, unless otherwise specified.)

| Characteristic | Symbol | Value | Unit |
|--|------------------|------------|------|
| Drain Source Voltage | V_{DSS} | 20 | V |
| Gate-Source Voltage | V _{GSS} | ±8 | V |
| Drain Current (Note 5) $ T_A = +25^{\circ}C $ $ T_A = +85^{\circ}C $ | l ln | 670 480 | mA |

Maximum Ratings P-CHANNEL − Q₂ (@T_A = +25°C, unless otherwise specified.)

| Characteristic | Symbol | Value | Unit |
|--|------------------|--------------|------|
| Drain Source Voltage | V_{DSS} | -20 | V |
| Gate-Source Voltage | V _{GSS} | ±8 | V |
| Drain Current (Note 5) $T_A = +25^{\circ}C$ $T_A = +85^{\circ}C$ | l ln | -530 -380 | mA |

Thermal Characteristics

| Characteristic | Symbol | Value | Unit |
|--|-----------------------------------|-------------|------|
| Power Dissipation (Note 5) | P_{D} | 400 | mW |
| Thermal Resistance, Junction to Ambient (Note 5) | $R_{	hetaJA}$ | 312.5 | °C/W |
| Operating and Storage Temperature Range | T _j , T _{STG} | -65 to +150 | °C |

Note: 5. Device mounted on FR-4 PCB.

Electrical Characteristics N-CHANNEL — Q₁ (@T_A = +25°C, unless otherwise specified.)

| Characteristic | Symbol | Min | Тур | Max | Unit | Test Condition |
|-----------------------------------|----------------------|-----|-----|-------|------|--------------------------------------|
| OFF CHARACTERISTICS (Note 6) | | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | 20 | _ | _ | V | $V_{GS} = 0V, I_D = 10\mu A$ |
| Zero Gate Voltage Drain Current | I _{DSS} | _ | _ | 1.0 | μA | $V_{DS} = 16V, V_{GS} = 0V$ |
| Gate-Source Leakage | I _{GSS} | _ | _ | ± 1.0 | μA | $V_{GS} = \pm 4.5V, V_{DS} = 0V$ |
| ON CHARACTERISTICS (Note 6) | | | | | | |
| Gate Threshold Voltage | V _{GS(th)} | 0.5 | _ | 1.0 | V | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ |
| | | _ | 0.4 | 0.55 | | $V_{GS} = 4.5V, I_D = 540mA$ |
| Static Drain-Source On-Resistance | R _{DS} (ON) | _ | 0.5 | 0.70 | Ω | $V_{GS} = 2.5V, I_D = 500mA$ |
| | | | 0.7 | 0.90 | | $V_{GS} = 1.8V, I_D = 350mA$ |
| Forward Transfer Admittance | Y _{fs} | 200 | _ | _ | mS | $V_{DS} = 10V, I_{D} = 0.2A$ |
| Diode Forward Voltage (Note 6) | V_{SD} | 0.5 | _ | 1.2 | V | $V_{GS} = 0V, I_{S} = 115mA$ |
| DYNAMIC CHARACTERISTICS | | | | | | |
| Input Capacitance | C _{iss} | _ | _ | 150 | pF | |
| Output Capacitance | | _ | _ | 25 | pF | $V_{DS} = 16V, V_{GS} = 0V$ |
| Reverse Transfer Capacitance | C _{rss} | _ | | 20 | pF | f = 1.0MHz |
| Reverse Transfer Capacitance | C _{rss} | | _ | 20 | pF | |

Notes: 6. Short duration pulse test used to minimize self-heating effect.



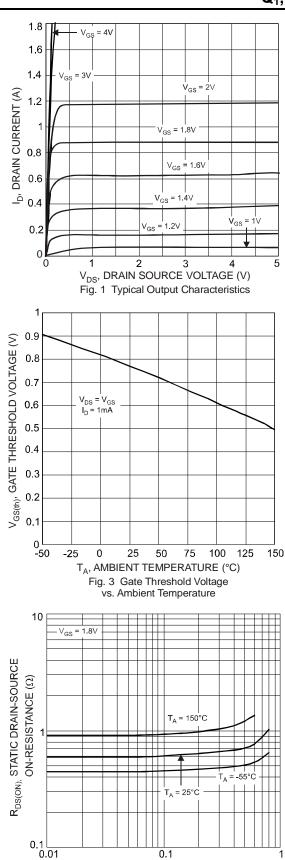
Electrical Characteristics P-CHANNEL – Q₂ (@T_A = +25°C, unless otherwise specified.)

| Characteristic | Symbol | Min | Тур | Max | Unit | Test Condition | |
|-----------------------------------|-----------------------------|------|--|-------------------|------|--|--|
| OFF CHARACTERISTICS (Note 6) | | | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | -20 | _ | _ | V | $V_{GS} = 0V$, $I_D = -250\mu A$ | |
| Zero Gate Voltage Drain Current | I _{DSS} | _ | _ | -1.0 | μA | $V_{DS} = -20V, V_{GS} = 0V$ | |
| Gate-Source Leakage | I _{GSS} | _ | _ | ± 1.0 | μA | $V_{GS} = \pm 4.5V, V_{DS} = 0V$ | |
| ON CHARACTERISTICS (Note 6) | ON CHARACTERISTICS (Note 6) | | | | | | |
| Gate Threshold Voltage | V _{GS(th)} | -0.5 | _ | -1.0 | V | $V_{DS} = V_{GS}, I_{D} = -250 \mu A$ | |
| Static Drain-Source On-Resistance | R _{DS} (ON) | _ | 0.7 1.1 1.7 | 0.9 1.4 2.0 | Ω | $V_{GS} = -4.5V$, $I_{D} = -430$ mA $V_{GS} = -2.5V$, $I_{D} = -300$ mA $V_{GS} = -1.8V$, $I_{D} = -150$ mA | |
| Forward Transfer Admittance | Y _{fs} | 200 | _ | | mS | $V_{DS} = 10V, I_D = 0.2A$ | |
| Diode Forward Voltage (Note 6) | V_{SD} | -0.5 | _ | -1.2 | V | $V_{GS} = 0V, I_{S} = -115mA$ | |
| DYNAMIC CHARACTERISTICS | | | | | | | |
| Input Capacitance | Ciss | _ | | 175 | pF | 101/1/ | |
| Output Capacitance | Casa 30 DF =* | | $V_{DS} = -16V, V_{GS} = 0V$ f = 1.0MHz | | | | |
| Reverse Transfer Capacitance | C _{rss} | _ | _ | 20 | pF | 71 = 1.0IVII IZ | |

Notes: 6. Short duration pulse test used to minimize self-heating effect.



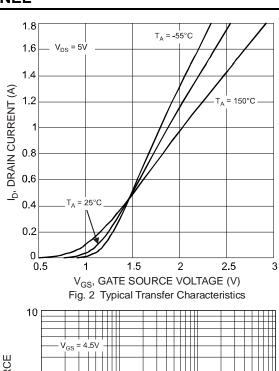
Q₁, N-CHANNEL



I_D, DRAIN CURRENT (A)

Fig. 5 Static Drain-Source On-Resistance

vs. Drain Current



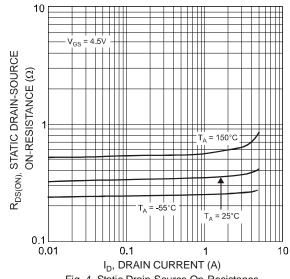


Fig. 4 Static Drain-Source On-Resistance vs. Drain Current

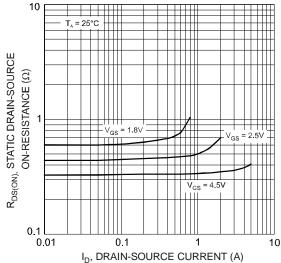


Fig. 6 Static Drain-Source On-Resistance vs. Drain-Source Current vs. Gate Source Voltage



Q₁, N-CHANNEL (cont.)

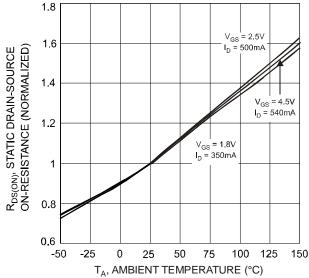


Fig. 7 Static Drain-Source On-State Resistance vs. Ambient Temperature

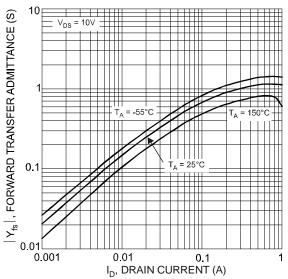


Fig. 9 Forward Transfer Admittance vs. Drain Current

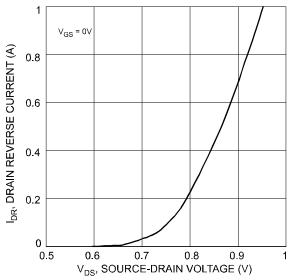
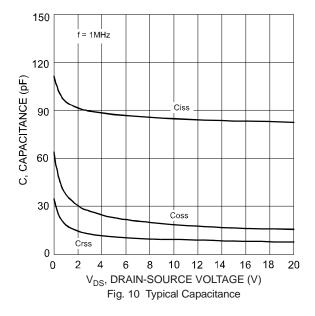
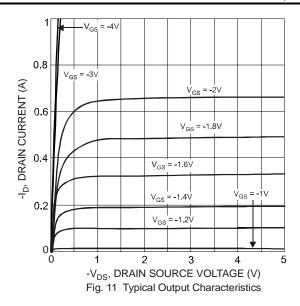


Fig. 8 Drain Reverse Current vs. Source-Drain Voltage





Q₂, P-CHANNEL



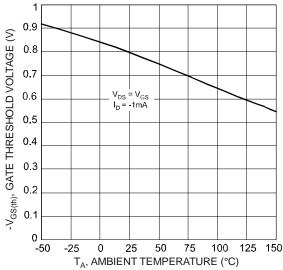


Fig. 13 Gate Threshold Voltage vs. Ambient Temperature

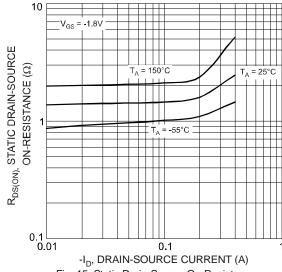
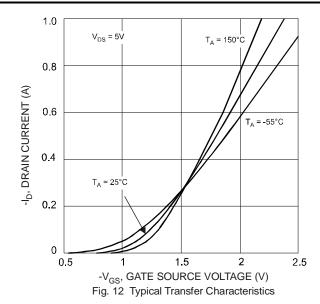


Fig. 15 Static Drain-Source On-Resistance vs.
Drain Current



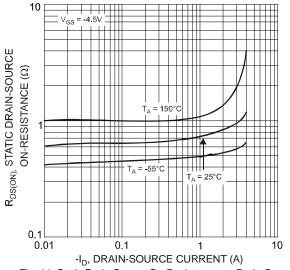


Fig. 14 Static Drain-Source On-Resistance vs. Drain Current

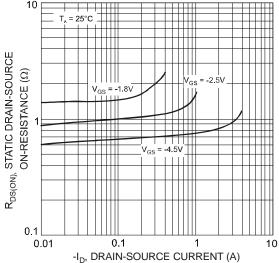


Fig. 16 Static Drain-Source On-Resistance vs. Drain-Source Current vs. Gate Source Voltage



Q₂, P-CHANNEL (cont.)

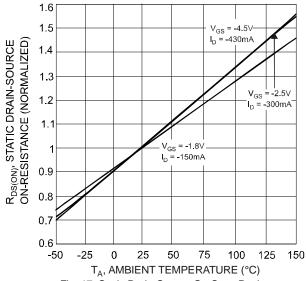


Fig. 17 Static Drain-Source On-State Resistance vs. Ambient Temperature

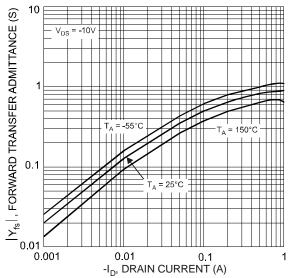


Fig. 19 Forward Transfer Admittance vs. Drain Current

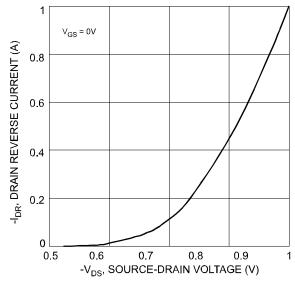
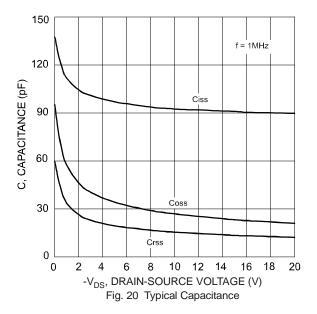
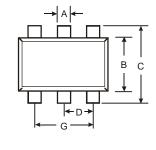


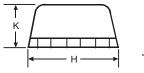
Fig. 18 Drain Reverse Current vs. Source-Drain Voltage

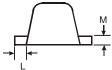




Package Outline Dimensions

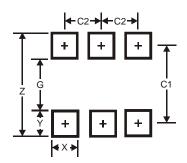






| SOT563 | | | | | | | |
|----------------------|------|------|------|--|--|--|--|
| Dim | Min | Max | Тур | | | | |
| Α | 0.15 | 0.30 | 0.20 | | | | |
| В | 1.10 | 1.25 | 1.20 | | | | |
| С | 1.55 | 1.70 | 1.60 | | | | |
| D | - | - | 0.50 | | | | |
| G | 0.90 | 1.10 | 1.00 | | | | |
| Н | 1.50 | 1.70 | 1.60 | | | | |
| K | 0.55 | 0.60 | 0.60 | | | | |
| ٦ | 0.10 | 0.30 | 0.20 | | | | |
| M | 0.10 | 0.18 | 0.11 | | | | |
| All Dimensions in mm | | | | | | | |

Suggested Pad Layout



| Dimensions | Value (in mm) |
|------------|---------------|
| Z | 2.2 |
| G | 1.2 |
| Х | 0.375 |
| Υ | 0.5 |
| C1 | 1.7 |
| C2 | 0.5 |



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